

## Silicon Errata for the CYT4BF Series Rev. D

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This document describes the errata for CYT4BF Rev. D Series of devices. Details include trigger conditions, scope of impact, available workarounds, and applicable silicon revisions. Contact your local Infineon Sales representative for further questions.

### Part Numbers Affected

Part Number
All CYT4BF Rev. D parts

### CYT4BF Rev. D Qualification Status

Product Status: Engineering Samples/Production Samples

### CYT4BF Rev. D Errata Summary

This table defines the errata applicable to CYT4BF Rev. D Series of devices.

Items	Part Number	Silicon Revision	Fix Status
Errata ID 96 <a href="#">CAN FD RX FIFO top pointer feature does not function as expected</a>	CYT4BF8CDDDES CYT4BF8CHDES CYT4BF8CCHDES CYT4BF8CEDQ0AESGS CYT4BF8CEDQ0AEEGS CYT4BF8CDDQ0AESGS CYT4BF8CDDQ0AEEGS CYT4BFBCJDQ0BZSGS CYT4BFBCJDQ0BZEGS CYT4BFBCJDQ0BZSGS CYT4BFBCJDQ0BZEGS CYT4BFCCJDQ0BZSGS CYT4BFCCJDQ0BZEGS CYT4BFCCJDQ0BZSGS CYT4BFCCJDQ0BZEGS CYT4BFCCJDQ0BZSGS CYT4BFCCJDQ0BZEGS	Rev. D	No silicon fix planned. Use workaround.
Errata ID 97 <a href="#">CAN FD debug message handling state machine not get reset to Idle state when CANFD_CH_CCCR.INIT is set</a>			No silicon fix planned. Use workaround.
Errata ID 124 <a href="#">Limitation of the memory hole in SCB register space</a>			No silicon fix planned. Use workaround.
Errata ID 128 <a href="#">Limitation of the memory hole in Ethernet (ETH) register space</a>			No silicon fix planned. Use workaround.
Errata ID 133 <a href="#">RMA failure</a>			No silicon fix planned. TRM was updated.
Errata ID 136 <a href="#">Secret Device Keys cannot be used</a>			Will be fixed in flash boot version 3.1.0.487 and later
Errata ID 137 <a href="#">Limitation of Work flash reading</a>			No silicon fix planned. Use workaround.
Errata ID 138 <a href="#">ROM boot code clears to zero first word of last 2 KB of SRAM</a>			No silicon fix planned. Use workaround.
Errata ID 139 <a href="#">Limitation of programming SFlash Normal Access Restrictions (row 13)</a>			No silicon fix planned. Use workaround.

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Items	Part Number	Silicon Revision	Fix Status
Errata ID 147 CAN FD controller message order inversion when transmitting from dedicated Tx Buffers configured with same Message ID			No silicon fix planned. Use workaround.
Errata ID 161 Boot time specifications are not correct			Datasheet (002-21617 Rev. *I) was updated.
Errata ID 163 RGMII rise/fall time was wrong			No silicon fix planned. Use workaround. Datasheet (002-21617 Rev. *I) was updated.
Errata ID 164 Addition of the sampling time spec for the temperature sensor			No silicon fix planned. Use workaround. Datasheet (002-21617 Rev. *I) was updated.
Errata ID 167 CAN FD incomplete description of Dedicated Tx Buffers and Tx Queue related to transmission from multiple buffers configured with the same Message ID			No silicon fix planned. Use workaround. TRM (002-24401 Rev. F) was updated.
Errata ID 168 DeepSleep wakeup time increases at cold temperature			No silicon fix planned. Datasheet (002-21617 Rev. *I) was updated.
Errata ID 169 IMO accuracy spec change			No silicon fix planned. Datasheet (002-21617 Rev. *K) was updated.
Errata ID 175 Misleading status is returned for Flash and eFuse system calls if there are pending NC ECC faults in SRAM controller #0			No silicon fix planned. TRM (002-24401 Rev. G) was updated.
Errata ID 176 WDT reset causes loss of SRAM retention			No silicon fix planned. TRM (002-24401 Rev. G) was updated.
Errata ID 177 RMII TX output maximum delay spec change for GPIO_STD			No silicon fix planned. Datasheet (002-21617 Rev. *J) was updated.
Errata ID 185 Crypto ECC errors may be set after boot with application authentication			No silicon fix planned. TRM (002-24401 Rev. G) was updated.
Errata ID 198 Incomplete erase of Code Flash cells could happen Erase Suspend / Erase Resume is used along with Erase Sector operation in Non-Blocking mode			Fixed to update the Flash settings from date code 312xxxxx
Errata ID 199 Limitation for keeping the port state from peripheral IP after wakeup from DeepSleep			No silicon fix planned. TRM (002-24401 Rev. G) was updated.

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Items	Part Number	Silicon Revision	Fix Status
Errata ID 201 <a href="#">A part of the PWR_CTL2.BGREF_LPMODE description is lacked in the existing register TRM</a>			No silicon fix planned. Register TRM (002-24402 Rev. *H) was updated.
Errata ID 202 <a href="#">Limitation of clock configuration before entering DeepSleep mode</a>			No silicon fix planned. TRM (002-24401 Rev. G) was updated.
Errata ID 203 <a href="#">Several data retention information in Register TRM are incorrect</a>			No silicon fix planned. Register TRM (002-24402 Rev. *H) was updated.
Errata ID 204 <a href="#">SCBx_INTR_TX.UNDERFLOW bit may be set unintentionally</a>			No silicon fix planned. Register TRM (002-24402 Rev. *H) was updated.
Errata ID 206 <a href="#">Hardfault may occur when calling some SROM APIs while executing EraseSector or ProgramRow in non-blocking mode</a>			No silicon fix planned. TRM (002-24401 Rev. H) will be updated.
Errata ID 209 <a href="#">CAN FD sporadic data corruption (payload) in case acceptance filtering is not finished before reception of data R3 (DB7..DB4) is completed</a>			No silicon fix planned. Use workaround.
Errata ID 212 <a href="#">Description for PASS SARx to TCPWMx direct connect triggers one-to-one is incorrect in datasheet</a>			No silicon fix planned. Datasheet (002-21617 Rev. *M) will be updated.

### 96. CAN FD RX FIFO top pointer feature does not function as expected

#### ■ Problem Definition

RX FIFO top pointer function calculates the address for received messages in Message RAM by hardware. This address should be re-start back from the start address after reading all messages of RX FIFO n size (n: 0 or 1). However, the address does not re-start back from the start address when RX FIFO n size is set to 1 (CANFD\_CH\_RXFnC.FnS = 0x01). This results in CPU/DMA to read messages from the wrong address in Message RAM.

#### ■ Parameters Affected

N/A

#### ■ Trigger Condition(s)

RX FIFO top pointer function is used when RX FIFO n size set to 1 element (CANFD\_CH\_RXFnC.FnS = 0x01).

#### ■ Scope of Impact

Received message cannot be correctly read by using RX FIFO top pointer function, when RX FIFO n size set to 1 element.

#### ■ Workaround

Any of the following.

- 1) Set RX FIFO n size to 2 or more when using RX FIFO top pointer function.
- 2) Do not use RX FIFO top pointer function when RX FIFO n size set to 1 element. Instead of RX FIFO top pointer, read received messages from the Message RAM directly.

#### ■ Fix Status

No silicon fix planned. Use workaround.

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### 97. CAN FD debug message handling state machine not get reset to Idle state when CANFD\_CH\_CCCR.INIT is set

#### ■ Problem Definition

If either CANFD\_CH\_CCCR.INIT bit is set by the Host or when the M\_TTCAN module enters BusOff state, the debug message handling state machine stays in its current state instead of being reset to Idle state. Configuring the bit CANFD\_CH\_CCCR.CCE does not change CANFD\_CH\_RXF1S.DMS.

#### ■ Parameters Affected

N/A

#### ■ Trigger Condition(s)

Either CANFD\_CH\_CCCR.INIT bit is set by the Host or when the M\_TTCAN module enters BusOff state.

#### ■ Scope of Impact

The errata is limited to the use case when the Debug on CAN functionality is active. Normal operation of CAN module is not affected, in which case the debug message handling state machine always remains in Idle state. In the described use case, the debug message handling state machine is stopped and remains in the current state signaled by the bit CANFD\_CH\_RXF1S.DMS. In case CANFD\_CH\_RXF1S.DMS is set to 0b11, DMA request remains active.

Bosch classifies this as non-critical error with low severity, there is no fix for the IP, Bosch recommends the workaround listed also here.

#### ■ Workaround

In case the debug message handling state machine has stopped while CANFD\_CH\_RXF1S.DMS is 0b01 or 0b10, it can be reset to Idle state by hardware reset or by reception of debug messages after CANFD\_CH\_CCCR.INIT is reset to zero.

#### ■ Fix Status

No silicon fix planned. Use workaround.

### 124. Limitation of the memory hole in SCB register space

#### ■ Problem Definition

The memory hole [offset address: 0x1000 to 0xFFFF] inside SCB register space is not aligned to the below defined spec. The offset address bits [15:12] are ignored and treated as 4'b0000, so write/read access to offset address [0x1000 to 0xFFFF], will actually happen to [0x0000 to 0x0FFF].

- Access to address gaps in mapped memory space: writes are ignored and any read returns a zero.

#### ■ Parameters Affected

N/A

#### ■ Trigger Condition(s)

Access to the memory hole [offset address: 0x1000 to 0xFFFF] in SCB register space.

#### ■ Scope of Impact

The memory hole [offset address: 0x1000 to 0xFFFF] in SCB register space is not aligned to other IP registers.

#### ■ Workaround

Do not access to the memory hole [offset address: 0x1000 to 0xFFFF] in SCB register space.

#### ■ Fix Status

No silicon fix planned. Use workaround.

### 128. Limitation of the memory hole in Ethernet (ETH) register space

#### ■ Problem Definition

The memory hole [offset address: 0x2000 to 0xFFFF] in ETH register space has the below mentioned original spec. However, when accessing to address gaps within [0x1000 to 0x1FFF], the offset address bits [15:13] are ignored and treated as 3'b000, so write/read access to offset address [0x3000 to 0x3FFF, 0x5000 to 0x5FFF, 0x7000 to 0x7FFF, 0x9000 to 0x9FFF, 0xB000 to 0xBFFF, 0xD000 to 0xDFFF, 0xF000 to 0xFFFF], will actually happen to [0x1000 to 0x1FFF].

- Access to address gaps within [0x0000 to 0x0FFF]: writes are ignored and any read returns a zero.

- Access to address gaps within [0x1000 to 0x1FFF]: returns AHB ERROR.

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- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
Access to the memory hole [offset address: 0x3000 to 0x3FFF, 0x5000 to 0x5FFF, 0x7000 to 0x7FFF, 0x9000 to 0x9FFF, 0xB000 to 0xBFFF, 0xD000 to 0xDFFF, 0xF000 to 0xFFFF] in ETH register space.
- **Scope of Impact**  
Write/read access to offset address [0x3000 to 0x3FFF, 0x5000 to 0x5FFF, 0x7000 to 0x7FFF, 0x9000 to 0x9FFF, 0xB000 to 0xBFFF, 0xD000 to 0xDFFF, 0xF000 to 0xFFFF], will actually happen to [0x1000 to 0x1FFF].
- **Workaround**  
Do not access to the memory hole [offset address: 0x3000 to 0x3FFF, 0x5000 to 0x5FFF, 0x7000 to 0x7FFF, 0x9000 to 0x9FFF, 0xB000 to 0xBFFF, 0xD000 to 0xDFFF, 0xF000 to 0xFFFF] in ETH register space.
- **Fix Status**  
No silicon fix planned. Use workaround.

### 133. RMA failure

- **Problem Definition**  
TransitionToRMA always fails due to hard fault resulting from access to protected memory (User SRAM except first 2 KB of SRAM0).
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
When using TransitionToRMA
- **Scope of Impact**  
TransitionToRMA always fails.
- **Workaround**  
None.
- **Fix Status**  
No silicon fix planned. Read and Write Access for PC1 shall be provided for the additional 2 KB of SRAM0 starting from SRAM0 + 2 KB. TRM was updated with this information.

### 136. Secret Device Keys cannot be used

- **Problem Definition**  
Secret Device Keys stored in eFuses can only be accessed by the crypto hardware module. Before the crypto module read the secret device keys, the eFuse read operation has to be enabled. Current protection configuration of device prevents any software from enabling the read operation. Attempt to load the secret device keys into the crypto module will result in all-'0' data being loaded as secret key. The failure is unascertainable to the user since no error is reported.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
Reading the secret device keys from eFuse
- **Scope of Impact**  
Secret device keys cannot be read from eFuse. All-'0' data will be used by the crypto module instead.
- **Workaround**  
None. Do not use the secret device key feature.
- **Fix Status**  
We will prepare new flash boot version (3.1.0.487 and later) to enable eFuse read. And we will also prepare the HSM performance library which supports to read the secret device keys.

### 137. Limitation of work flash reading

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- **Problem Definition**
  1. Work flash can be read via different CPU cores but only one CPU core is assigned for non-correctable ECC error handling.
  2. Reading 32 bits of work flash on AXI bus can result in ECC error.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**
  1. Reading work flash via CPU core (CM0+, CM7\_0/1) and ECC fault interrupt routed to two or more CPU cores.
  2. Reading 32 bits of work flash via CM7\_0/1 or other AXI master and adjacent 32 bits of work flash is not initialized.
- **Scope of Impact**
  1. Only one CPU core can be assigned for non-correctable ECC error handling.
  2. Work flash should be accessed via AHB or AXI with 64-bit boundary.
- **Workaround**  
Any of the following:  
Option A (Recommended solution).  
Problem 1 and problem 2: Set each CPU core to use a separate AHB DMA (M-DMA or P-DMA) channel to read work flash. If non-correctable ECC error occurs, the DMA transaction get aborted and respective CPU core gets the interrupt to manage the non-correctable ECC error.  
  
Option B.  
Problem 1<sup>[1]</sup>: Set non-correctable ECC error handling to reset. This way no one CPU core needs to manage the non-correctable ECC error handling.  
Problem 2: Limit work flash data size to 64 bits. Program work flash in units of aligned 64-bit double words and read it as 64-bit double words thru CM7\_0/1 or another AXI master.  
  
Note [1]: Not recommended to use for EEPROM emulation. EEPROM emulation needs to cope with aborted write/erase. In such a scenario, option B leads to deadlock in endless resets. However, option B can be used if work flash update is not intended in the field.  
  
Option C.  
Problem 1<sup>[2]</sup>: Assign one CPU core for non-correctable ECC error handling and that core informs the error to the other core which caused the error, but it takes time.  
Problem 2: Use Option B.  
  
Note [2]: Not recommended to use with MCAL, since the inter-core communication is too slow.
- **Fix Status**  
No silicon fix planned. Use workaround.  
Infineon FLS and FEE driver were updated with workaround A.  
TRM was updated for this limitation.

### 138. ROM boot code clears to zero first word of last 2 KB of SRAM

- **Problem Definition**  
ROM boot code clears to zero first word of last 2 KB of SRAM. This region is available to the user after boot. However, data retention across resets is not guaranteed in this area.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
After ROM boot

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- **Scope of Impact**  
Data retention across resets is not guaranteed in first word of last 2 KB of SRAM.
- **Workaround**  
Do not use first word of last 2 KB of SRAM for data retention.
- **Fix Status**  
No silicon fix planned. Use workaround.  
TRM was updated for this limitation.

### 139. Limitation of programming SFlash Normal Access Restrictions (row 13)

- **Problem Definition**  
CM0+ cache is not disabled when programming SFlash Normal Access Restrictions (row 13) by WriteRow SROM API. Occasionally, writing to SFlash Normal Access Restrictions (row 13) may return error status "0xF00000A4" (ProgramRow is invoked on unerased cells or blank check fails).
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
WriteRow SROM API is called on Normal Access Restrictions (row 13).
- **Scope of Impact**  
Error status – 0xF00000A4 "ProgramRow is invoked on unerased cells or blank check fails" is returned.
- **Workaround**  
Disable CM0+ cache before call to WriteRow (to SFlash row 13) and enabling the cache back after the SROM API execution. Following sequence could be a recommended sequence:  
 1) FLASHC\_CM0\_CA\_CTL0.CA\_EN = 0; // Disable the CM0+ cache  
 2) Trigger WriteRow SROM API on NAR (row 13)  
 3) WriteRow successful  
 4) FLASHC\_CM0\_CA\_CTL0.CA\_EN = 1; // Enable the CM0+ cache
- **Fix Status**  
No silicon fix planned. Use workaround.  
TRM was updated for this limitation.

### 147. CAN FD controller message order inversion when transmitting from dedicated Tx Buffers configured with same Message ID

- **Problem Definition**  
Configuration:  
Several Tx Buffers are configured with same Message ID. Transmission of these Tx Buffers is requested sequentially with a delay between the individual Tx requests.
- Expected behavior:  
When multiple Tx Buffers that are configured with the same Message ID have pending Tx requests, they shall be transmitted in ascending order of their Tx Buffer numbers. The Tx Buffer with lowest buffer number and pending Tx request is transmitted first.
- Observed behavior:  
It may happen, depending on the delay between the individual Tx requests, that in the case where multiple Tx Buffers are configured with the same Message ID the Tx Buffers are not transmitted in order of the Tx Buffer number (lowest number first).
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
When multiple Tx Buffers that are configured with the same Message ID have pending Tx requests.

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### ■ Scope of Impact

In the case described it may happen, that Tx Buffers configured with the same Message ID and pending Tx request are not transmitted with lowest Tx Buffer number first (message order inversion).

### ■ Workaround

Any of the following:

- 1) First write the group of Tx message with the same Message ID to the Message RAM and then afterwards request transmission of all these messages concurrently by a single write access to CANFDx\_CHy\_TXBAR. Before requesting a group of Tx messages with this Message ID ensure that no message with this Message ID has a pending Tx request.
- 2) Use the Tx FIFO instead of dedicated Tx Buffers for the transmission of several messages with the same Message ID in a specific order.

Applications not able to use workaround #1 or #2 can implement a counter within the data section of their messages sent with same ID in order to allow the recipients to determine the correct sending sequence.

### ■ Fix Status

No silicon fix planned. Use workaround.

## 161. Boot time specifications are not correct

### ■ Problem Definition

TRAVEO™ T2G silicon's shipped until now (flash boot version earlier than 3.1.0.554) have a higher boot time compared to what is mentioned in datasheet rev. H.

### ■ Parameters Affected

SID80A, SID80B, SID81A, SID81B

### ■ Trigger Condition(s)

Device boot

### ■ Scope of Impact

System startup time will be longer than expected.

### ■ Workaround

None

### ■ Fix Status

Boot time specifications was updated in datasheet (002-21617 Rev. \*I) for existing devices (flash boot version earlier than 3.1.0.554):

SID80A\_2: 2640  $\mu$ s

SID80B\_2: 3890  $\mu$ s

SID81A\_2: 200  $\mu$ s

SID81B\_2: 10000  $\mu$ s

## 163. RGMII rise/fall time was wrong

### ■ Problem Definition

RGMII rise/fall time (SID365B: 0.99 ns) was wrong. It was not aligned with the standard spec. 0.75 ns is a correct spec value.

### ■ Parameters Affected

SID365B

### ■ Trigger Condition(s)

Using RGMII

### ■ Scope of Impact

New correct spec (0.75 ns) will be tighter than the existing spec (0.99 ns).

### ■ Workaround

Use RGMII with new spec (SID365B1: 0.75 ns).



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- **Fix Status**

No silicon fix planned. Use workaround.  
Datasheet (002-21617 Rev. \*I) was updated.

### 164. Addition of the sampling time spec for the temperature sensor

- **Problem Definition**

Existing datasheet (rev. H) didn't have defined the sampling time spec for the temperature sensor. The settling time for the temperature sensor needs to be included in the sampling time of ADC.

- **Parameters Affected**

N/A

- **Trigger Condition(s)**

Using the temperature sensor

- **Scope of Impact**

For the temperature sensor, the sampling time needs to be longer than normal A/D conversion.

- **Workaround**

Set the sampling time to 7  $\mu$ s and more.

- **Fix Status**

No silicon fix planned. Use workaround.  
Datasheet (002-21617 Rev. \*I) was updated to add the sampling time spec for the temperature sensor.

### 167. CAN FD incomplete description of Dedicated Tx Buffers and Tx Queue related to transmission from multiple buffers configured with the same Message ID

- **Problem Definition**

The following is the updated description in Section 3.5.2 Dedicated Tx Buffers and 3.5.4 Tx Queue of the Architecture TRM related to transmission from multiple buffers configured with the same Message ID.

#### 3.5.2 Dedicated Tx Buffers

- Wording TRM:

If multiple Tx Buffers are configured with the same Message ID, the Tx Buffer with the lowest buffer number is transmitted first.

- Enhancement:

These Tx buffers shall be requested in ascending order with lowest buffer number first. Alternatively all Tx buffers configured with the same Message ID can be requested simultaneously by a single write access to CANFDx\_CHy\_TXBAR.

#### 3.5.4 Tx Queue

- Wording TRM:

If multiple queue buffers are configured with the same Message ID, the queue buffer with the lowest buffer number is transmitted first.

- Replacement:

In case that multiple Tx Queue buffers are configured with the same Message ID, the transmission order depends on numbers of the buffers where the messages were stored for transmission. As these buffer numbers depend on the then current states of the PUT Index, a prediction of the transmission order is not possible.

- Wording TRM:

An Add Request cyclically increments the Put Index to the next free Tx Buffer.

- Replacement:

The PUT Index always points to that free buffer of the Tx Queue with the lowest number.

- **Parameters Affected**

N/A

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- **Trigger Condition(s)**  
Using multiple dedicated Tx Buffers or Tx Queue Buffers configured with the same Message ID.
- **Scope of Impact**  
In the case the dedicated Tx Buffers with the same Message ID are not requested in ascending order or at the same time or in case of multiple Tx Queue Buffers with the same Message ID, it cannot be guaranteed, that these messages are transmitted in ascending order with lowest buffer number first.
- **Workaround**  
In case a defined order of transmission is required the Tx FIFO shall be used for transmission of messages with the same Message ID. Alternatively dedicated Tx Buffers with the same Message ID shall be requested in ascending order with lowest buffer number first or by a single write access to CANFDx\_CHy\_TXBAR. Alternatively a single Tx Buffer can be used to transmit those messages one after the other.
- **Fix Status**  
No silicon fix planned. Use workaround. TRM (002-24401 Rev. F) was updated accordingly.

### 168. DeepSleep wakeup time increases at cold temperature

- **Problem Definition**  
DeepSleep wakeup time increases at cold temperature (-5 °C to -40 °C).
- **Parameters Affected**  
SID67/A/B/C/D
- **Trigger Condition(s)**  
DeepSleep wakeup at cold temperature (-5 °C to -40 °C)
- **Scope of Impact**  
DeepSleep wakeup time increases at cold temperature (-5 °C to -40 °C).
- **Workaround**  
None
- **Fix Status**  
No silicon fix planned. The following note was added to the affected SIDs in the datasheet (002-21617 Rev. \*I).  
Note: At cold temperature -5 °C to -40 °C, the DeepSleep to Active transition time can be higher than the max time indicated by as much as 20 µs

### 169. IMO accuracy spec change

- **Problem Definition**  
IMO accuracy spec is changed from +/- 1% to +/- 4% because IMO is not trimmed after DeepSleep wakeup.
- **Parameters Affected**  
SID310
- **Trigger Condition(s)**  
Using IMO
- **Scope of Impact**  
IMO accuracy spec change
- **Workaround**  
None
- **Fix Status**  
No silicon fix planned. SID310 was updated in datasheet (002-21617 Rev. \*I). Root and intermediate clocks table was updated as below in datasheet (002-21617 Rev. \*K).

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Clock	Maximum permitted clock frequency (MHz) [1]	Source	Maximum permitted clock frequency setting (MHz) [1]					
			PLL/FLL Clock source: ECO [2]			PLL/FLL Clock source: IMO [3]		
			Integer	SSCG	Fractional	Integer	SSCG	Fractional
CLK_HF0	200	PLL200#0	200	N/A	N/A	190	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
	100	PLL200#0	100	N/A	N/A	98	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF1	350	PLL400#0	350	340	344	333	326	330
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF2	100	PLL200#1	100	N/A	N/A	98	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF3	100	PLL200#0	100	N/A	N/A	98	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF4	125	PLL400#1	125	122	122	119	117	117
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF5	196.608	PLL400#1	196.608	193	196.608	189	185	187
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF6	200	PLL200#0	200	N/A	N/A	190	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_HF7	8	ILO	N/A	N/A	N/A	N/A	N/A	N/A
CLK_FAST_0	350	PLL400#0	350	340	344	333	326	330
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_FAST_1	350	PLL400#0	350	340	344	333	326	330
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_MEM	200	PLL200#0	200	N/A	N/A	190	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
	100	PLL200#0	100	N/A	N/A	98	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_SLOW	100	PLL200#0	100	N/A	N/A	98	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A
CLK_PERI	100	PLL200#0	100	N/A	N/A	98	N/A	N/A
		FLL	100	N/A	N/A	96	N/A	N/A

[1]: Maximum clock frequency after the corresponding clock source (PLL/FLL + dividers). All internal tolerances and affects are covered by these frequencies.

[2]: For ECO: up to  $\pm 150$  ppm uncertainty of the external clock source are tolerated by design.

[3]: For IMO: the IMO operation frequency tolerance is included. When DeepSleep mode isn't used, maximum permitted clock frequency setting of clock source IMO case is equal to clock source ECO case.

#### 175. Misleading status is returned for Flash and eFuse system calls if there are pending NC ECC faults in SRAM controller #0

##### ■ Problem Definition

Flash and eFuse system calls will return misleading status of 0xf0000005 ("Page is write protected") even

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for non-protected row or 0xf0000002 (“Invalid eFuse address”) for valid eFuse address in case of pending NC ECC faults in SRAM controller #0.

- **Parameters Affected**  
Return status of Flash and eFuse system calls
- **Trigger Condition(s)**  
NC ECC fault(s) pending in SRAM controller #0 and SWPUs are populated in the design.
- **Scope of Impact**  
Flash and eFuse system calls will not work until the NC ECC fault(s) pending in SRAM controller #0 is properly handled.
- **Workaround**  
If the NC ECC fault(s) are not due to HW malfunction (i.e., if the faults are due to usage of non-initialized SRAM or improper SRAM initialization), then clearing of these pending faults will resolve the issue.
- **Fix Status**  
No silicon fix planned. TRM (002-24401 Rev. G) was updated.

### 176. WDT reset causes loss of SRAM retention

- **Problem Definition**  
Architecture TRM Table 19-1 shows WDT reset can retain SRAM if there is an orderly shutdown of the SRAM only during a warning interrupt. However, this is wrong. WDT reset causes loss of SRAM retention.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
WDT reset
- **Scope of Impact**  
WDT reset causes loss of SRAM retention.
- **Workaround**  
None
- **Fix Status**  
No silicon fix planned. TRM (002-24401 Rev. G) was updated.

### 177. RMII TX output maximum delay spec change for GPIO\_STD

- **Problem Definition**  
RMII TX output maximum delay specification has been changed from 14 ns to 14.6 ns for GPIO\_STD. The CYT4BF (272/320-BGA) HSIO\_STD spec of 14ns is unchanged.
- **Parameters Affected**  
SID393
- **Trigger Condition(s)**  
Using GPIO\_STD as RMII
- **Scope of Impact**  
This spec change will cause that the PCB delay budget between MCU and PHY cut down to 1.4 ns from 2 ns. [PCB delay budget = REF\_CLK period (e.g. 20 ns) – SID393 (14.6 ns) – PHY RXD setup (e.g. 4 ns)]
- **Workaround**  
None
- **Fix Status**  
No silicon fix planned. Datasheet (002-21617 Rev. \*J) was updated.

### 185. Crypto ECC errors may be set after boot with application authentication

- **Problem Definition**  
Due to the improper initialization of the Crypto memory buffer, Crypto ECC errors may be set after boot with application authentication. In spite of the Crypto ECC errors, the result of the authentication is reliable.

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- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
Boot device with application authentication.
- **Scope of Impact**  
Crypto ECC errors may be set after boot with application authentication.
- **Workaround**  
Clear or ignore Crypto ECC errors which generated during boot with application authentication.
- **Fix Status**  
No silicon fix planned. TRM (002-24401 Rev. G) was updated.

### 198. Incomplete erase of Code Flash cells could happen Erase Suspend / Erase Resume is used along with Erase Sector operation in Non-Blocking mode

- **Problem Definition**  
Code Flash memory can be erased in “Non-Blocking” mode; a Non-Blocking mode supported option allow users to suspend an ongoing erase sector operation. When an ongoing erase operation is interrupted using “Erase Suspend” and “Erase Resume”, Flash cells may not have been erased completely, even after the erase operation complete is indicated by FLASHC\_STATUS register. Only Code Flash is impacted by this issue, Work Flash and Supervisory Flash (SFlash) are not impacted.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
Using EraseSector System Call in Non-Blocking mode for CM0+ to erase Code Flash and the ongoing erase operation is interrupted using EraseSuspend and EraseResume System calls.
- **Scope of Impact**  
When Code Flash sectors are erased in Non-Blocking mode and the ongoing erase operation is interrupted by Erase Suspend / Erase Resume, it cannot be guaranteed that the Code Flash cells are fully erased. Any read on the Code Flash area after the erase is complete or read on the programmed data after ProgramRow is complete can trigger ECC errors.
- **Workaround**  
Use any of the following:  
1) User can use Non-Blocking mode for EraseSector, but users must not interrupt the erase operation using Erase Suspend / Erase Resume.  
2) If a Code Flash sector erase operation is interrupted using Erase Suspend / Erase Resume, then erase the same sector again without Erase Suspend / Erase Resume before reading the sector or programming the sector.
- **Fix Status**  
Fixed to update the Flash settings from date code 312xxxxx, via Manufacturing Test Program Update for Code Flash setting; this fix is transferred to TRAVEO™ T2G devices during Infineon Factory Test Flow. Fixed devices will be identified by Device Date Code, which is marked on every TRAVEO™ T2G device.

### 199. Limitation for keeping the port state from peripheral IP after wakeup from DeepSleep

- **Problem Definition**  
The port state is not retained when the port selects peripheral IP (except for LIN or CAN FD) and MCU wakes up from DeepSleep.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
The port selects peripheral IP (except for LIN or CAN FD) and MCU wakes up from DeepSleep.
- **Scope of Impact**  
Unexpected port output change might affect user system.

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### ■ Workaround

If the port selects peripherals IP (except for LIN or CAN FD) and the port output value need to keep after wakeup from DeepSleep, set HSIOM\_PRTx\_PORT\_SEL.IOy\_SEL = 0 (GPIO) before DeepSleep and set the required output value in GPIO configuration registers. After wakeup, change HSIOM\_PRTx\_PORT\_SEL.IOy\_SEL back to the peripheral IP.

### ■ Fix Status

No silicon fix planned. TRM (002-24401 Rev. G) was updated to add above workaround.

## 201. A part of the PWR\_CTL2.BGREF\_LPMODE description is lacked in the existing register TRM

### ■ Problem Definition

The following is lacked from the PWR\_CTL2.BGREF\_LPMODE description in the existing register TRM. "This register will not set unless CLK\_ILO0\_CONFIG.ILO0\_ENABLE==1. When changing back to continuous operation, keep ILO0 enabled for at least 5 ILO0 cycles after clearing this bit to allow for internal synchronization."

### ■ Parameters Affected

N/A

### ■ Trigger Condition(s)

Using the PWR\_CTL2.BGREF\_LPMODE

### ■ Scope of Impact

PWR\_CTL2.BGREF\_LPMODE may not be set or cleared.

### ■ Workaround

Use the PWR\_CTL2.BGREF\_LPMODE according to the following description.

"This register will not set unless CLK\_ILO0\_CONFIG.ILO0\_ENABLE==1. When changing back to continuous operation, keep ILO0 enabled for at least 5 ILO0 cycles after clearing this bit to allow for internal synchronization."

### ■ Fix Status

No silicon fix planned. Register TRM (002-24402 Rev. \*H) was updated.

## 202. Limitation of clock configuration before entering DeepSleep mode

### ■ Problem Definition

DeepSleep should not be entered while any FLL/PLL is enabled and using ECO as its reference clock. Since the unstable ECO clock after wakeup is outside the allowed reference clock limits for FLL/PLL, there is possibility of failing the DeepSleep wakeup.

### ■ Parameters Affected

N/A

### ■ Trigger Condition(s)

DeepSleep transition while any FLL/PLL is enabled and using ECO as its reference clock.

### ■ Scope of Impact

There is possibility of failing the DeepSleep wakeup.

### ■ Workaround

If any FLL/PLL is operating with the ECO as its reference clock, change the clock to either ECO direct or IMO direct or IMO with FLL/PLL before entering DeepSleep.

### ■ Fix Status

No silicon fix planned. TRM (002-24401 Rev. G) was updated to add above workaround.

## 203. Several data retention information in Register TRM are incorrect

### ■ Problem Definition

The following registers are described as 'Retained' in the Register TRM while it is not guaranteed that the value before entering DeepSleep mode is still readable from the register.

- SARADC: PASSx\_SARy\_CHz\_RESULT
- SRSS: PWR\_LVD\_STATUS

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- SRSS: PWR\_LVD\_STATUS2
- SRSS: CLK\_CAL\_CNT1
- SRSS: CLK\_CAL\_CNT2
- SRSS: CLK\_FLL\_STATUS
- ~~SRSS: WDT\_CNT~~ (It is retained during DeepSleep or Hibernate if DPSLP\_PAUSE == 1 or HIB\_PAUSE == 1)
- SRSS: WDT\_INTR
- SRSS: WDT\_INTR\_MASKED
- SRSS: CLK\_PLL400Mx\_STATUS

▪ **Parameters Affected**

N/A

▪ **Trigger Condition(s)**

Use of the related function and wakeup from DeepSleep mode.

▪ **Scope of Impact**

The values before entering DeepSleep are not retained.

▪ **Workaround**

For PASSx\_SARy\_CHz\_RESULT, any of following:

- 1) Store the conversion values at another memory location before entering DeepSleep mode
- 2) Restart the conversion after wakeup from DeepSleep mode

For the other registers:

Rewrite the register value or read the status flags again after wakeup.

▪ **Fix Status**

No silicon fix planned. Register TRM (002-24402 Rev. \*H) was updated.

### 204. SCBx\_INTR\_TX.UNDERFLOW bit may be set unintentionally

▪ **Problem Definition**

There is possibility of setting the SCBx\_INTR\_TX.UNDERFLOW bit even if the FIFO is not empty.

▪ **Parameters Affected**

N/A

▪ **Trigger Condition(s)**

Using the TX FIFO for SCB when the AHB-Lite interface clock (CLK\_GR6) frequency of the AHB bus is greater than 3x the SCB functionality clock (PCLK\_SCBx\_CLOCK).

▪ **Scope of Impact**

SCBx\_INTR\_TX.UNDERFLOW bit may be set unintentionally.

▪ **Workaround**

Ignore the SCBx\_INTR\_TX.UNDERFLOW bit if the FIFO is not empty.

▪ **Fix Status**

No silicon fix planned. Register TRM (002-24402 Rev. \*H) was updated.

### 206. Hardfault may occur when calling **some SROM APIs** while executing EraseSector or ProgramRow in non-blocking mode

▪ **Problem Definition**

The following **SROM APIs** read data from bank#0 (or bank#1 if dual bank mode with mapping B is used) in SFlash. While doing that the check for active non-blocking erase or program of bank#0 (or bank#1 if dual bank mode with mapping B is used) is not performed. Therefore, reading bank#0 (or bank#1 if dual bank mode with mapping B is used) while there is an active erase/program operation will trigger a bus error which can result in a hardfault occurrence based on FLASHC\_FLASH\_CTL register settings.

**Affected SROM APIs:**

- ReadSWPU
- WriteSWPU
- **GenerateHash**

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- Checksum\*
- ComputeBasicHash\*
- CheckFactoryHash
- ProgramWorkFlash\*\*
- SwitchOverRegulators
- LoadRegulatorsTrims

\*: Note that it should not be called if you programming/erasing bank that you are going to calculate.

\*\*: Note that it is not possible to use it during non-blocking operation.

■ **Parameters Affected**

N/A

■ **Trigger Condition(s)**

Calling **the affected SROM APIs** while executing EraseSector or ProgramRow in non-blocking mode on bank#0 (or bank#1 if dual bank mode with mapping B is used).

■ **Scope of Impact**

**The affected SROM APIs** cannot be used while executing EraseSector or ProgramRow in non-blocking mode on bank#0 (or bank#1 if dual bank mode with mapping B is used).

■ **Workaround**

Do not use **the affected SROM APIs** while executing EraseSector or ProgramRow in non-blocking mode on bank#0 (or bank#1 if dual bank mode with mapping B is used).

■ **Fix Status**

No silicon fix planned. TRM (002-24401 Rev. H) **will be** updated.

■ **Impact on Infineon Software**

Impact: Limitation

Related modules: S-LLD, HSM-Perf-Lib

Comment: While executing EraseSector or ProgramRow in non-blocking mode on bank#0 (or bank#1 if dual bank mode with mapping B is used), users must not do anything of following:

- a) call CySldProt\_GetSwpuFlashStructCfg
- b) call CySldProt\_VerifySecureDomainFlashWriteProtection if CySldProt\_SwpuFlashStructGroupConfigurations is non-empty.

### 209. CAN FD sporadic data corruption (payload) in case acceptance filtering is not finished before reception of data R3 (DB7..DB4) is completed

■ **Problem Definition**

During frame reception the Rx Handler accesses the external Message RAM for acceptance filtering (read accesses) and for storing of the accepted messages (write accesses).

The time needed for acceptance filtering and for storing of a received message depends on

- the Host clock frequency
- the worst-case latency of the read and write accesses to the external Message RAM
- the number of configured filter elements
- the workload of the transmit message (Tx) handler in parallel to the receive message (Rx) handler

Received data bytes (DB0..DBm) from the CAN Core are buffered in the cache of the Rx Handler before they are written to the Message RAM (in words of 4 byte). Data words inside the Message RAM are numbered from R2 to Rn ( $n \leq 17$ ).



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	31	24	23	16	15	8	7	0	
R0	ESI	XTD	RTR	ID[28:0]					
R1A	ANMF	FIDX[6:0]		res	FDF	BRS	DLC[3:0]	RXTS[15:0]	
R1B	ANMF	FIDX[6:0]		res	FDF	BRS	DLC[3:0]	res	TSC RXTSP [3:0]
R2	DB3[7:0]		DB2[7:0]		DB1[7:0]		DB0[7:0]		
R3	DB7[7:0]		DB6[7:0]		DB5[7:0]		DB4[7:0]		
...	...		...		...		...		
Rn	DBm[7:0]		DBm-1[7:0]		DBm-2[7:0]		DBm-3[7:0]		

Figure 1. Rx Buffer and FIFO Element

Under the following conditions a received message will have corrupted data while the received message is signaled as valid to the host.

- 1) The data length code (DLC) of the received Message is greater than 4 ( $DLC > 4$ )
- 2) The storage of  $R_i$  of a received message into the Message RAM (after acceptance filtering is done) has not completed before  $R_{(i+1)}$  is transferred from the CAN Core into the cache of the Rx Handler (where  $2 \leq i \leq 5$ ).
- 3) While condition 1) and 2) apply, a concurrent read of data word  $R_i$  from the cache and write of data word  $R_{(i+1)}$  into the cache of the Rx handler happens.

The data will be corrupted in a way, that in the Message RAM  $R_{(i+1)}$  has the same content as  $R_i$ .

Despite the corrupted data, the M\_TTCAN signals the storage of a valid frame in the Message RAM:

- Rx FIFO: FIFO put index  $RXF_nS.FnPI$  is updated.
- Dedicated Rx Buffer: New Data flag  $NDAT_n.NDxx$  is set.
- Interrupt flag  $IR.MRAF$  is not set.

The issue may occur in FD Frame Format as well as in Classic Frame Format.

Figure 2 shows how the available time for acceptance filtering and storage is reduced.

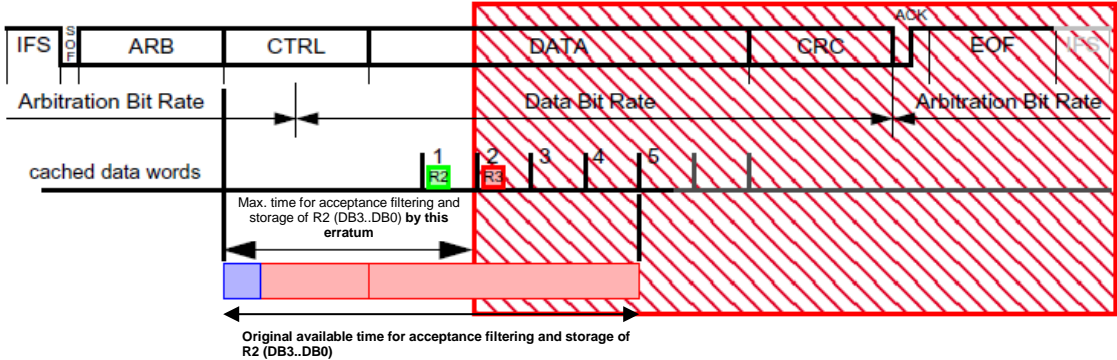


Figure 2. CAN Frame with  $DLC > 4$

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Table 1. TRAVEO T2G: Minimum host clock frequency for CAN FD when DLC = 5

Number of configured active filter element 11-bit IDs / 29-bit IDs 1,2	Number of active CAN channels in an instance	Arbitration bit rate = 0.5 Mbps				Arbitration bit rate = 1 Mbps			
		Data bit rate = 0.5 Mbps	Data bit rate = 1 Mbps	Data bit rate = 2 Mbps	Data bit rate = 4 Mbps	Data bit rate = 1 Mbps	Data bit rate = 2 Mbps	Data bit rate = 4 Mbps	Data bit rate = 5 Mbps
32 / 16	2	3.9 MHz	7.1 MHz	13.1 MHz	22.8 MHz	7.7 MHz	14.1 MHz	26.1 MHz	31.5 MHz
	3	5.4 MHz	9.9 MHz	18.3 MHz	31.8 MHz	10.7 MHz	19.7 MHz	36.5 MHz	44.0 MHz
	4	6.9 MHz	12.7 MHz	23.5 MHz	40.8 MHz	13.8 MHz	25.3 MHz	46.9 MHz	56.5 MHz
	5	8.4 MHz	15.5 MHz	28.6 MHz	49.9 MHz	16.8 MHz	30.9 MHz	57.2 MHz	69.0 MHz
64 / 32	2	7.4 MHz	13.5 MHz	24.9 MHz	43.4 MHz	14.7 MHz	26.9 MHz	49.8 MHz	60.0 MHz
	3	10.3 MHz	18.8 MHz	34.9 MHz	60.7 MHz	20.5 MHz	37.6 MHz	69.7 MHz	84.0 MHz
	4	13.2 MHz	24.2 MHz	44.8 MHz	78.0 MHz	26.3 MHz	48.4 MHz	89.5 MHz	107.9 MHz <sup>3</sup>
	5	16.1 MHz	29.6 MHz	54.7 MHz	95.3 MHz	32.1 MHz	59.1 MHz	109.4 MHz <sup>3</sup>	131.8 MHz <sup>3</sup>
96 / 48	2	10.8 MHz	19.9 MHz	36.8 MHz	64.0 MHz	21.6 MHz	39.7 MHz	73.5 MHz	88.6 MHz
	3	15.1 MHz	27.8 MHz	51.5 MHz	89.6 MHz	30.2 MHz	55.6 MHz	102.9 MHz <sup>3</sup>	124.0 MHz <sup>3</sup>
	4	19.4 MHz	35.7 MHz	66.1 MHz	115.1 MHz <sup>3</sup>	38.8 MHz	71.4 MHz	132.2 MHz <sup>3</sup>	159.3 MHz <sup>3</sup>
	5	23.7 MHz	43.6 MHz	80.8 MHz	140.7 MHz <sup>3</sup>	47.4 MHz	87.2 MHz	161.5 MHz <sup>3</sup>	194.7 MHz <sup>3</sup>
128 / 64	2	14.3 MHz	26.3 MHz	48.6 MHz	84.7 MHz	28.4 MHz	52.5 MHz	97.2 MHz	117.2 MHz <sup>3</sup>
	3	20.0 MHz	36.8 MHz	68.0 MHz	118.5 MHz <sup>3</sup>	40.0 MHz	73.5 MHz	136.0 MHz <sup>3</sup>	164.0 MHz <sup>3</sup>
	4	25.7 MHz	47.2 MHz	87.5 MHz	152.3 MHz <sup>3</sup>	51.4 MHz	94.4 MHz	174.9 MHz <sup>3</sup>	210.8 MHz <sup>3</sup>
	5	31.4 MHz	57.7 MHz	106.9 MHz <sup>3</sup>	186.1 MHz <sup>3</sup>	62.7 MHz	115.4 MHz <sup>3</sup>	213.7 MHz <sup>3</sup>	257.5 MHz <sup>3</sup>

1. M\_TTCAN starts always at filter element #0 and proceeds through the filter list to find a matching element. Acceptance filtering stops at the first matching element and the following filter elements are not evaluated for this message. Therefore, the sequence of configured filter elements has a significant impact on the performance of the filtering process.
2. Acceptance filtering search for 11-bit IDs and 29-bit IDs filter element is running separately, only one configured filter setting should be considered. Searching for one 29-bit filter element requires approximately double cycles for one 11-bit filter element.
3. Frequency is not reachable since the maximum host clock frequency for M\_TTCAN in TRAVEO™ T2G is 100 MHz.

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### Parameters Affected

N/A

### Trigger Condition(s)

Under the following conditions a received message will have corrupted data while the received message is signaled as valid to the host.

- 1) The data length code (DLC) of the received Message is greater than 4 ( $DLC > 4$ )
- 2) The storage of  $R_i$  of a received message into the Message RAM (after acceptance filtering is done) has not completed before  $R_{(i+1)}$  is transferred from the CAN Core into the cache of the Rx Handler (where  $2 \leq i \leq 5$ ).
- 3) While condition 1) and 2) apply, a concurrent read of data word  $R_i$  from the cache and write of data word  $R_{(i+1)}$  into the cache of the Rx handler happens.

### Scope of Impact

The erratum is limited to the case when the Host clock frequency used in the actual device is below the limit shown in Table 1.

Corrupted data is written to the Rx FIFO element respective the dedicated Rx Buffer.

The received frame is nevertheless signaled as valid.

### Workaround

Check whether the minimum Host clock frequency, that is shown in Table 1, is below the Host clock frequency used in the actual device.

If yes, there is no problem with the selected configuration.

If no, use one of the following two workarounds.

#### First workaround

Try different configuration by changing the following parameters until the actual host clock frequency (CLK\_GR5) is above the minimum host frequency shown in Table 1.

- Increase the CLK\_GR5 frequency in the actual device
- Reduce the CAN-FD Data Bit rate
- Reduce the number of configured filter elements
- Reduce the number of active CAN channels in an instance

Also, use  $DLC \geq 8$  instead of DLCs 5, 6, and 7 in the CAN Environment/System, as they place higher demands on the minimum Host clock frequency (the worst case is  $DLC=5$ ) or restrict your CAN Environment/System to DLC 4.

Note: While changing the actual host clock frequency, CLK\_GR5 must always be equal or higher than PCLK\_CANFD[x]\_CLOCK\_CAN[y] for all configurations.

#### Second workaround

Due to condition 3) the issue occurs only sporadically. Use an end-to-end (E2E) protection (for example, checksum or CRC covering the data field) and add it to all messages in the CAN system, to detect data corruption in received frames.

### Fix Status

No silicon fix planned. Use workaround.

### Impact on Infineon Software

Impact: Limitation

Related modules: CAN, MCU

Comment: The user must evaluate the impact of the erratum for each CAN instance separately. A CAN instance is the entirety of CanControllers with the same CanControllerInstance value.

- 1) For the number of active CAN nodes: Use the maximum number of CanController configurations of a CAN instance that can be active (Autosar controller state STARTED or SLEEP) at a time.

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- 2) For the host clock frequency: In McuPeriGroupSettings locate the setting with McuPeriGroup=MCU\_PERI\_GROUP5\_MMIO5 and take the value from McuPeriGroupClockFrequency.
- 4) For the number of configured active filter element 11-bit IDs / 29-bit IDs: Use the corresponding values from the “Message RAM (...) linking table” in the generated Can\_PBcfg.h file. Note that each CanController has its separate table. Take the maximum values.
- 5) For the Arbitration bit rate: Use the maximum CanControllerBaudRate value of all the CanControllers.
- 6) For the Data bit rate: Use the maximum CanControllerFdBaudRate value of all the CanControllers if configured. Otherwise use CanControllerBaudRate.

### 212. Description for PASS SARx to TCPWMx direct connect triggers one-to-one is incorrect in datasheet

- **Problem Definition**  
The existing datasheet shows ‘trig=2’ in the description for PASS SARx to TCPWMx direct connect triggers one-to-one, which is incorrect as TCPWM’s input trigger selection (TR\_IN\_SEL) value. The correct value is ‘4’ as shown in the architecture TRM chapter 25 descriptions and table 25-2.
- **Parameters Affected**  
N/A
- **Trigger Condition(s)**  
Using the triggers one-to-one for PASS SARx to TCPWMx direct connect
- **Scope of Impact**  
The triggers one-to-one for PASS SARx to TCPWMx direct connect cannot work if TCPWM’s input trigger selection is not correct.
- **Workaround**  
Use ‘4’ as TCPWM’s input trigger selection (TR\_IN\_SEL) value for PASS SARx to TCPWMx direct connect
- **Fix Status**  
No silicon fix planned. Datasheet (002-21617 Rev. M) will be updated.
- **Impact on Infineon Software**  
Impact: No  
Related modules: PWM  
Comment: MCAL PWM module does not support one-to-one triggers.

## Silicon Errata for the CYT4BF Series Rev. D

### Revision history

Document revision	Date of release	Description of Change
1.0	2020-05-14	Initial release
1.1	2020-06-17	Added errata ID 133.
1.2	2020-08-28	Updated the 'Fix Status' in errata ID 133. Added errata ID 136 to 139.
1.3	2021-02-18	Added errata ID 147.
1.4	2021-06-29	Added errata ID 161, 163, 164.
1.5	2021-09-16	Updated "Workaround" of errata ID 147. Added errata ID 167, 168, 169.
1.6	2022-01-21	Added errata ID 175, 176, 177.
1.7	2022-07-04	Updated "Fixed status" of errata ID 169. Added errata ID 185.
1.8	2022-08-25	Updated "Problem Definition" of errata ID 185. Added errata ID 198, 199.
1.9	2022-12-02	Added errata ID 201, 202, 203, 204.
2.0	2023-02-08	Updated the description to 5 ILO0 cycles in errata ID 201. Updated "Problem Definition" of errata ID 203. Fixed the register name of errata ID 204. Added errata ID 206.
2.1	2023-06-15	Updated descriptions of errata ID 133. Updated errata ID 206 to add (or bank#1 if dual bank mode with mapping B is used). Added errata ID 209.
2.2	2023-10-17	Updated errata ID 206 to add the affected SROM APIs. Added errata ID 212.

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